

ABSTRACT

A method for testing integrated circuits, including measuring a current signature delta value of a device under test and comparing the current signature delta value to a threshold current signature delta value to determine whether the current signature delta value is greater than the threshold current signature delta value. If the current signature delta value exceeds the threshold current signature delta value, the integrated circuit is rejected. Integrated circuits are also rejected if the post-stress current signature value exceeds a maximum current signature value, even though the current signature delta value is less than the threshold current signature delta value. In addition, an apparatus for testing integrated circuits is disclosed.